

Approval Sheet

Customer	
Product Number	M3MW-4GSSPL0C-D
Module speed	PC3-12800
Pin	244 pin
CI-tRCD-tRP	11-11-11
SDRAM Operating Temp	0°C~85°C
Date	29 th August 2016

Approval by Customer

P/N:

Signature:

Date:

Sales: _____ Sr. Technical Manager: John Hsieh

Rev 1.0

1. Features

Key Parameter

Industry Nomenclature	Speed Grade	Data Rate MT/s			tAA (ns)	tRCD (ns)	tRP (ns)
		CL=7	CL=9	CL=11			
PC3-12800	P	1066	1333	1600	13.125	13.125	13.125

- JEDEC Standard 244-pin Dual In-Line Memory Module
- Intend for PC3-12800 applications
- Inputs and Outputs are SSTL-15 compatible
- VDD=VDDQ= 1.35 Volt (-0.067/+0.1V) or 1.5 Volt (-0.075/+0.075V)
- Bi-directional Differential Data Strobe
- DLL aligns DQ and DQS transition with CK transition
- SDRAMs have 8 internal banks for concurrent operation
- Normal and Dynamic On-Die Termination support.
- SDRAMs are 78-ball BGA Package
- Very Low-profile PCB design
- 8 bit pre-fetch
- Two different termination values (Rtt_Nom & Rtt_WR)
- Auto & self refresh 7.8 μ s ($T_c \leq +85^{\circ}C$)
- 16/10/1 Addressing (row/column/rank)-4GB
- SDRAM IC operating temperature range
 - $0^{\circ}C \leq T_c \leq +85^{\circ}C$
- Programmable Device Operation:
 - Burst Type: Sequential or Interleave
 - Device CAS# Latency: 7, 9, 11
 - Burst Length: switch on-the-fly: BL=8 or BC 4
- ECC Function
- RoHS Compliant

2. Environmental Requirements

iDIMM are intended for use in standard office environments that have limited capacity for heating and air conditioning.

Symbol	Parameter	Rating	Units	Notes
TOPR	Operating Temperature (ambient)	0 to +65	°C	1
TSTG	Storage Temperature	-50 to +100	°C	
HOPR	Operating Humidity (relative)	10 to 90	%	
HSTG	Storage Humidity (without condensation)	5 to 95	%	
PBAR	Barometric Pressure (operating & storage)	105 to 69	K Pascal	1,2

1. The component maximum case temperature (Tcase) shall not exceed the value specified in the DDR DRAM component specification.
2. Up to 9850 ft.

3. DRAM Parameters by device density

RTT_Nom Setting	Parameter	8Gb	Units
tRFC	REF command ACT or REF command time	260	ns
tREFI	Average periodic refresh interval	$0^{\circ}\text{C} \leq \text{T}_{\text{CASE}} \leq 85^{\circ}\text{C}$	7.8 μs
		$85^{\circ}\text{C} \leq \text{T}_{\text{CASE}} \leq 95^{\circ}\text{C}$	3.9 μs

4. Ordering Information

VLP DDR3L Mini-RDIMM						
Part Number	Density	Speed	DIMM Organization	Number of DRAM	Number of rank	ECC
M3MW-4GSSPL0C-D	4GB	PC3-12800	512Mx72	9	1	Y

5. Pin Configurations (Front side/Back side)

X72 Mini-RDIMM

Pin	Front	Pin	Back	Pin	Front	Pin	Back	Pin	Front	Pin	Back
1	VTT	41	CB1	82	Vss	123	VTT	163	Vss	204	DQ36
2	Vrefca	42	Vss	83	DQ32	124	Vss	164	DM8 or TDQS17 **	205	DQ37
3	Vss	43	/DQS8	84	DQ33	125	DQ4	165	NC *or /TDQS17 **	206	Vss
4	DQ0	44	DQS8	85	Vss	126	DQ5	166	Vss	207	DM4 or TDQS13 **
5	DQ1	45	Vss	86	/DQS4	127	Vss	167	CB6	208	NC *or /TDQS13 **
6	Vss	46	CB2	87	DQS4	128	DM0 or TDQS9 **	168	CB7	209	Vss
7	/DQS0	47	CB3	88	Vss	129	NC * or /TDQS9 **	169	Vss	210	DQ38
8	DQS0	48	Vss	89	DQ34	130	Vss	170	NC *	211	DQ39
9	Vss	49	NC *	90	DQ35	131	DQ6	171	NC *	212	Vss
10	DQ2	50	/Reset	91	Vss	132	DQ7	172	NC * or CKE1 **	213	DQ44
11	DQ3	51	CKE0	92	DQ40	133	Vss	173	Vss	214	DQ45
12	Vss	52	Vss	93	DQ41	134	DQ12	174	A15	215	Vss
13	DQ8	53	BA2	94	Vss	135	DQ13	175	A14	216	DM5 or TDQS14**
14	DQ9	54	NC* or Err_Out **	95	/DQS5	136	Vss	176	Vss	217	NC *or /TDQS14**
15	Vss	55	Vss	96	DQS5	137	DM1 or TDQS10 **	177	A12	218	Vss
16	/DQS1	56	A11	97	Vss	138	NC *or /TDQS10 **	178	A9	219	DQ46
17	DQS1	57	A7	98	DQ42	139	Vss	179	Vss	220	DQ47
18	Vss	58	Vss	99	DQ43	140	DQ14	180	A8	221	Vss
19	DQ10	59	A5	100	Vss	141	DQ15	181	A6	222	DQ52
20	DQ11	60	A4	101	DQ48	142	Vss	182	Vss	223	DQ53
21	Vss	61	Vss	102	DQ49	143	DQ20	183	A3	224	Vss
22	DQ16	62	A2	103	Vss	144	DQ21	184	A1	225	DM6 or TDQS15 **
23	DQ17	63	Vss	104	/DQS6	145	Vss	185	Vss	226	NC *or /TDQS15 **
24	Vss	64	CK1 or NA**	105	DQS6	146	DM2 or TDQS11 **	186	CK0	227	Vss
25	/DQS2	65	/CK1 or NA**	106	Vss	147	NC *or /TDQS11 **	187	/CK0	228	DQ54
26	DQS2	66	Vss	107	DQ50	148	Vss	188	Vss	229	DQ55
27	Vss	67	Vrefca	108	DQ51	149	DQ22	189	Vss	230	Vss
28	DQ18	68	Vss	109	Vss	150	DQ23	190	/EVENT	231	DQ60
29	DQ19	69	NC * or Par_in **	110	DQ56	151	Vss	191	A0	232	DQ61
30	Vss	70	Vss	111	DQ57	152	DQ28	192	Vss	233	Vss
31	DQ24	71	A10	112	Vss	153	DQ29	193	BA1	234	DM7 or TDQS16 **
32	DQ25	72	BA0	113	/DQS7	154	Vss	194	Vss	235	NC *or /TDQS16 **
33	Vss	73	Vss	114	DQS7	155	DM3 or TDQS12 **	195	/RAS	236	Vss
34	/DQS3	74	/WE	115	Vss	156	NC *or /TDQS12 **	196	/CS0	237	DQ62
35	DQS3	75	/CAS	116	DQ58	157	Vss	197	Vss	238	DQ63
36	Vss	76	Vss	117	DQ59	158	DQ30	198	ODT0	239	Vss
37	DQ26	77	NC * or /CS1 **	118	Vss	159	DQ31	199	A13	240	Vssop
38	DQ27	78	NC * or ODT1 **	119	SA0	160	Vss	200	Vss	241	SA1
39	Vss	79	Vss	120	SCL	161	CB4	201	NC *	242	SDA
40	CB0	80	NC *	121	SA2	162	CB5	202	NC *	243	Vss
		81	NC *	122	VTT			203	Vss	244	VTT

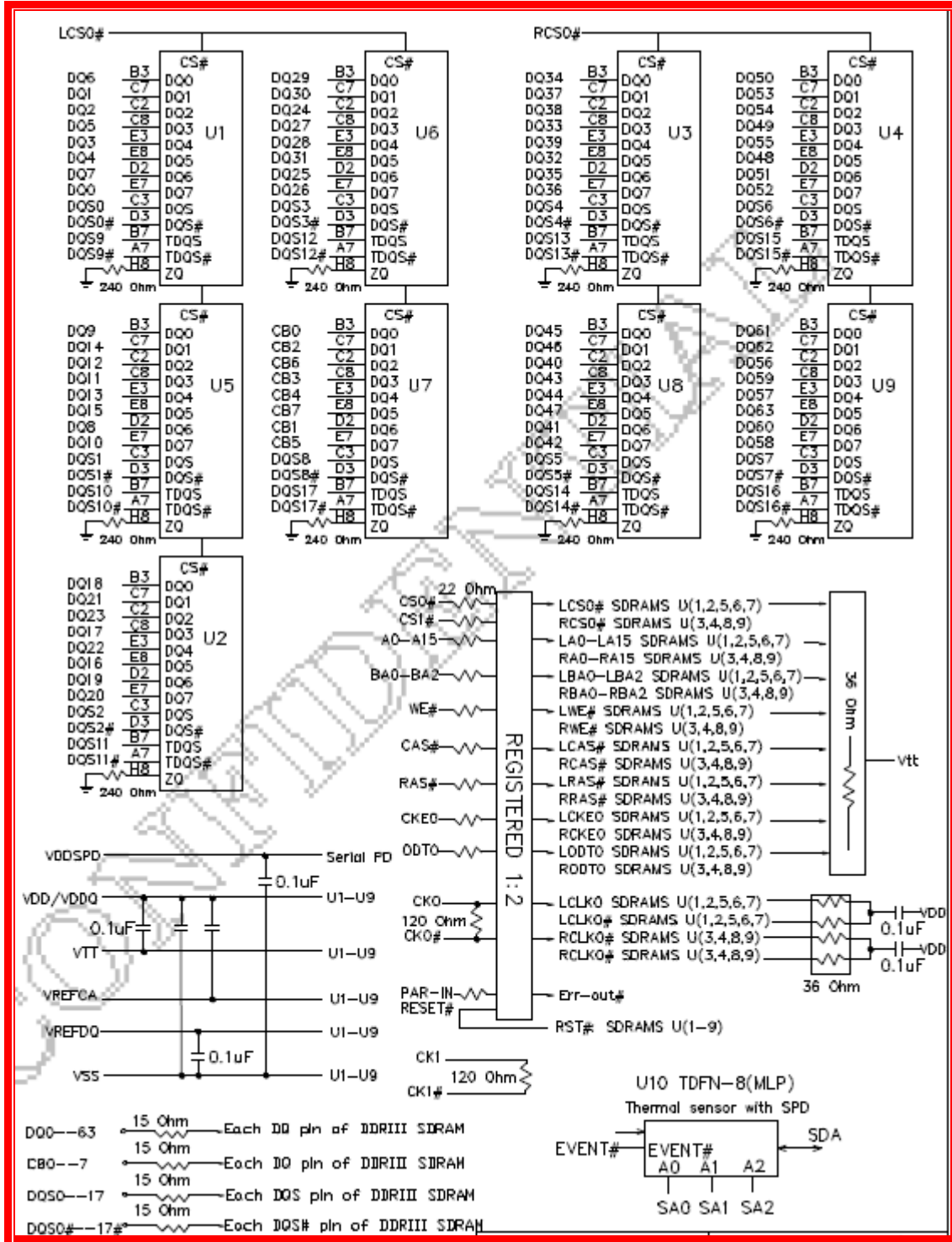
** NC = No Connect
 ** 2 Ranks MiniDIMM use.
 *** Pin might connected to NC ball or DRAMs (depending on density); alternatively may connect to termination resistor

6. Architecture

Pin Definition

Pin Name	Description	Pin Name	Description
A0 - A15	SDRAM address bus	SCL	Serial Presence Detect Clock Input
BA0 – BA2	SDRAM Bank Address Inputs	SDA	Serial Presence Detect Data input/output
/RAS	SDRAM row address strobe	SA0 – SA2	Serial Presence Detect Address Inputs
/CAS	SDRAM column address strobe	V _{DD}	Power Supply
/WE	SDRAM write enable	V _{DDID}	V _{DD} Identification Flag
/CS0 - /CS1	DIMM Rank Select Lines	V _{DDQ}	SDRAM I/O Driver power supply
CK0 – CK1	SDRAM clock enable lines	V _{REFDQ}	SDRAM I/O Reference supply
DQ0 – DQ63	DIMM memory data bus	V _{REFCA}	SDRAM Command/address reference supply.
CB0 – CB7	DIMM ECC check bit	V _{SS}	Ground
DQS0 – DQS8 /DQS0-/DQS8	SDRAM data strobes	V _{DDSPD}	Serial EEPROM positive power supply
DM0 – DM8	SDRAM data masks	NC	Spare Pin
ODT0-ODT1	Spare Pin	/Reset	Reset enable
CK0 – CK1 /CK0 - /CK1	Differential SDRAM Clocks	Event#	Reserved for optional temperature-sensing hardware
RSVD	Reserved for future use.	V _{TT}	SDRAM I/O termination supply.
A10 / AP	Auto-precharge	A12 /BC	Burst Chop
ZQ	Reference Pin for ZQ calibration		

7. Function Block Diagram:
 - (4GB, 1 Rank, 512Mx8 DDR3 SDRAMs)



8. DRAM Absolute Maximum Ratings

Symbol	Parameter	Rating	Units	Note	
T _{OPER}	Operation Temperature	Normal Operating Temp.	0 to 85	°C	1,2
		Extended Temp.(optional)	85 to 95	°C	1,3
T _{STG}	Storage Temperature	-55 to 100	°C	4,5	
V _{IN} , V _{OUT}	Voltage on any pins relative to V _{ss}	-0.4 to +1.975	V	4	
V _{DD}	Voltage on VDD supply relative to V _{ss}	-0.4 to +1.975	V	4,6	
V _{DDQ}	Voltage on VDDQ supply relative to V _{ss}	-0.4 to +1.975	V	4,6	

Note:

1. Operating Temperature T_{OPER} is the case surface temperature on the center / top side of the DRAM.

For measurement conditions, please refer to the JEDEC document JESD51-2.

2. The Normal Temperature Range specifies the temperatures where all DRAM specifications will be supported. During operation, the DRAM case temperature must be maintained between 0 to 85 °C under all operating conditions.

3. Some applications require operation of the DRAM in the Extended Temperature Range between 85 °C and 95 °C case temperature. Full specifications are supported in this range, but the following additional conditions apply:

- a) Refresh commands must be doubled in frequency, therefore reducing the Refresh interval tREFI to 3.9 μs. It is also possible to specify a component with 1X refresh (tREFI to 7.8μs) in the Extended Temperature Range. Please refer to supplier data sheet and/or the DIMM SPD for option availability.
- b) If Self-Refresh operation is required in the Extended Temperature Range, then it is mandatory to either use the Manual Self-Refresh mode with Extended Temperature Range capability (MR2 A6 =0b and MR2 A7 = 1b) or enable the optional Auto Self-Refresh mode (MR2 A6 = 1b and MR2 A7 =0b). Please refer to the supplier data sheet and/or the DIMM SPD for Auto Self-Refresh option availability, Extended Temperature Range support and tREFI requirements in the Extended Temperature Range.

4. Stresses greater than those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is stress rating only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

5. Storage Temperature is the case surface temperature on the center/top side of the DRAM. For the measurement conditions, please refer to JESD51-2 standard.

6. VDD and VDDQ must be within 300 mV of each other at all times;and VREF must be not greater than 0.6 x VDDQ, When VDD and VDDQ are less than 500 mV; VREF may be equal to or less than 300 mV

9. DRAM AC & DC Operating

Symbol	Parameter	Min	Typ.	Max	Units	Notes
Recommended DC Operating Conditions						
V_{DD}	Supply Voltage	1.283	1.35	1.45	V	1,2
V_{DDQ}	Supply Voltage	1.283	1.35	1.45	V	1,2
Single Ended AC/DC Input Levels						
V_{IH} (DC)	DC Input High (Logic1) Voltage	$V_{REF} + 0.1$	-	V _{DD}	V	3
V_{IL} (DC)	DC Input Low (Logic 0) Voltage	V _{SS}	-	$V_{REF} - 0.1$	V	3
V_{IH} (AC)	AC Input High (Logic1) Voltage	$V_{REF} + 0.175$	-	-	V	3
V_{IL} (AC)	AC Input Low (Logic 0) Voltage	-	-	$V_{REF} - 0.175$	V	3
V_{REFDQ} (DC)	Reference Voltage for DQ, DM inputs	0.49V _{DDQ}	0.5V _{DDQ}	0.51V _{DDQ}	V	4,5
V_{REFCA} (DC)	Reference Voltage for ADD,CMD inputs	0.49V _{DDQ}	0.5V _{DDQ}	0.51V _{DDQ}	V	4,5
Single Ended AC/DC output Levels						
V_{OH} (DC)	DC output high measurement level (for IV curve linearity)	-	0.8 x V _{DDQ}	-	V	
V_{OM} (DC)	DC output mid measurement level (for IV curve linearity)	-	0.5 x V _{DDQ}	-	V	
V_{OL} (DC)	DC output low measurement level (for IV curve linearity)	-	0.2 x V _{DDQ}	-	V	
V_{OH} (AC)	AC output high measurement level (for output SR)	-	$V_{TT} + 0.1 \times V_{DDQ}$	-	V	6
V_{OL} (AC)	AC output low measurement level (for output SR)	-	$V_{TT} - 0.1 \times V_{DDQ}$	-	V	6

Symbol	Parameter	Min	Typ.	Max	Units	Notes
Differential AC/DC Input Levels						
VIHdiff	Differential Input high	+0.2	-	Note 9	V	7
VILdiff	Differential Input logic Low	Note 9	-	-0.2	V	7
VIHdiff(ac)	Differential Input high ac	2* (VIH (AC)- VREF)	-	Note 9	V	8
VILdiff(ac)	Differential Input logic Low ac	Note 9	-	2* (VREF- VIL (AC))	V	8
Differential AC and DC Output Levels						
VOHdiff(AC)	AC differential output high measurement level (for output SR)	-	+ 0.2 x VDDQ	-	V	10
VOLdiff(AC)	AC differential output low measurement level (for output SR)	-	- 0.2 x VDDQ	-	V	10
Note:						
<ol style="list-style-type: none"> Under all conditions VDDQ must be less than or equal to VDD. VDDQ tracks with VDD. AC parameters are measured with VDD and VDDQ tied together. For DQ and DM, Vref = VrefDQ. For input only pins except RESET#, Vref = VrefCA. The ac peak noise on VRef may not allow VRef to deviate from VRef(DC) by more than +/-1% VDD (for reference: approx. +/- 15 mV). For reference: approx. VDD/2 +/- 15 mV. The swing of $\pm 0.1 \times VDDQ$ is based on approximately 50% of the static single-ended output high or low swing with a driver impedance of 40Ω and an effective test load of 25Ω to $VTT = VDDQ/2$ Used to define a differential signal slew-rate. For CK - CK# use VIH/VIL(ac) of ADD/CMD and VREFCA; for DQS - DQS#, DQSL, DQSL#, DQSU, DQSU# use VIH/VIL(ac) of DQs and VREFDQ; if a reduced ac-high or ac-low level is used for a signal group, then the reduced level applies also here. These values are not defined, however the single-ended signals CK, CK#, DQS, DQS#, DQSL, DQSL#, DQSU, DQSU# need to be within the respective limits (VIH(dc) max, VIL(dc)min) for single- ended signals as well as the limitations for overshoot and undershoot. The swing of $\pm 0.2 \times VDDQ$ is based on approximately 50% of the static single-ended output high or low swing with a driver impedance of 40Ω and an effective test load of 25Ω to $VTT = VDDQ/2$ at each of the differential outputs. 						

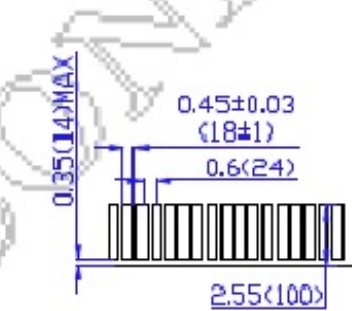
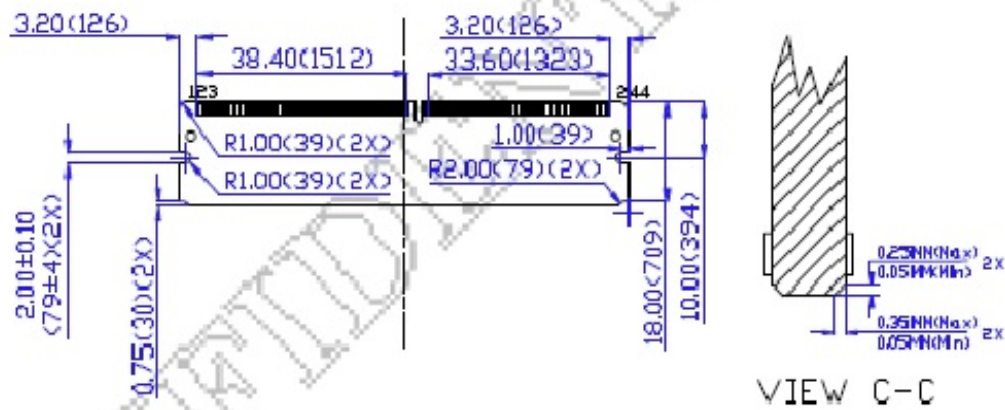
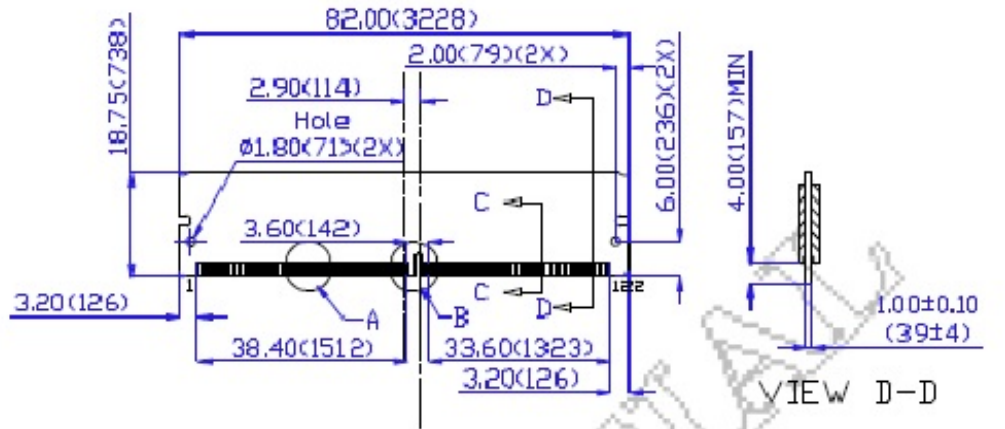
10. Operating, Standby, and Refresh Currents

- 4GB ECC Mini-RDIMM (1 Rank, 512Mx8 DDR3 SDRAMs $T_{CASE} = 0\text{ }^{\circ}\text{C} \sim 85\text{ }^{\circ}\text{C}$)

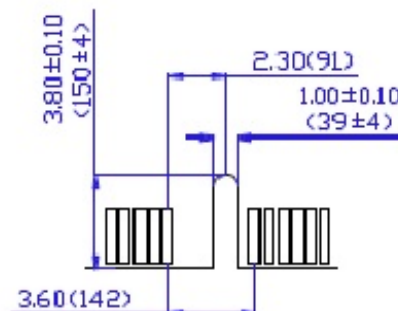
Symbol	Parameter/Condition		PC3-12800	Unit
I DD0	One bank; Active - Precharge		234	mA
I DD1	One bank; Active - Read - Precharge		324	mA
I DD2N	Precharge Standby Current		99	mA
IDD2NT	Precharge Standby ODT Current		117	mA
I DD2P	Precharge Power Down Current	Fast Mode	72	mA
	Precharge Power Down Current	Slow Mode	72	mA
I DD2Q	Precharge Quiet Standby Current		90	mA
I DD3N	Active Standby Current		189	mA
I DD3P	Active Power-Down Current		90	mA
I DD4R	Operating Current Burst Read		576	mA
I DD4W	Operating Current Burst Write		567	mA
I DD5B	Burst Refresh Current		1710	mA
I DD6	Self-Refresh Current: Normal Temperature Range		108	mA
I DD7	Operating Bank Interleave Read Current		1089	mA
I DD8	RESET Low Current		135	mA

11. PACKAGE DIMENSION

- (4GB, 1 Rank, 512Mx8 DDR3 base Mini-RDIMM w/ECC)



Detail A



Detail B

Note: All dimensions are in millimeters (mils) and should be kept within a tolerance of ± 0.15 (6), unless otherwise specified.

12. RoHS Declaration

innodisk	宜鼎國際股份有限公司 Innodisk Corporation														
Tel:(02)7703-3000 Fax:(02) 7703-3555 Internet: http://www.innodisk.com/															
RoHS 自我宣告書 (RoHS Declaration of Conformity)															
Manufacturer Product: All Innodisk EM Flash and Dram products															
<p>一、 宜鼎國際股份有限公司（以下稱本公司）特此保證售予貴公司之所有產品，皆符合歐盟 2011/65/EU 關於 RoHS 之規範要求。</p> <p>Innodisk Corporation declares that all products sold to the company, are complied with European Union RoHS Directive (2011/65/EU) requirement</p>															
<p>二、 本公司同意因本保證書或與本保證書相關事宜有所爭議時，雙方宜友好協商，達成協議。</p> <p>Innodisk Corporation agrees that both parties shall settle any dispute arising from or in connection with this Declaration of Conformity by friendly negotiations.</p>															
<table border="1"> <thead> <tr> <th>Name of hazardous substance</th> <th>Limited of RoHS ppm (mg/kg)</th> </tr> </thead> <tbody> <tr> <td>Cd</td> <td>< 100 ppm</td> </tr> <tr> <td>Pb</td> <td>< 1000 ppm</td> </tr> <tr> <td>Hg</td> <td>< 1000 ppm</td> </tr> <tr> <td>Chromium VI (Cr+6)</td> <td>< 1000 ppm</td> </tr> <tr> <td>Polybromodiphenyl ether (PBDE)</td> <td>< 1000 ppm</td> </tr> <tr> <td>Polybrominated Biphenyls (PBB)</td> <td>< 1000 ppm</td> </tr> </tbody> </table>	Name of hazardous substance	Limited of RoHS ppm (mg/kg)	Cd	< 100 ppm	Pb	< 1000 ppm	Hg	< 1000 ppm	Chromium VI (Cr+6)	< 1000 ppm	Polybromodiphenyl ether (PBDE)	< 1000 ppm	Polybrominated Biphenyls (PBB)	< 1000 ppm	
Name of hazardous substance	Limited of RoHS ppm (mg/kg)														
Cd	< 100 ppm														
Pb	< 1000 ppm														
Hg	< 1000 ppm														
Chromium VI (Cr+6)	< 1000 ppm														
Polybromodiphenyl ether (PBDE)	< 1000 ppm														
Polybrominated Biphenyls (PBB)	< 1000 ppm														
立 保 證 書 人 (Guarantor)															
Company name 公司名稱： <u>Innodisk Corporation 宜鼎國際股份有限公司</u>															
Company Representative 公司代表人： <u>Richard Lee 李鐘亮</u>															
Company Representative Title 公司代表人職稱： <u>CEO 執行長</u>															
Date 日期： <u>2014 / 07 / 29</u>															
<div style="border: 1px dashed black; padding: 5px; display: inline-block;">  </div> <p>(Company Seals/公司大小章)</p>															

Revision Log

Rev	Date	Modification
0.1	29 th August 2016	Preliminary Edition
1.0	29 th August 2016	Official released.